

# **MOSFET** – Power, N-Channel

## 100 V, 4.0 $m\Omega$

## **NVCR4LS004N10MCA**

## **Features**

- Typical  $R_{DS(on)} = 3.2 \text{ m}\Omega$  at  $V_{GS} = 10 \text{ V}$
- Typical  $Q_{g(tot)} = 47 \text{ nC}$  at  $V_{GS} = 10 \text{ V}$
- AEC-Q101 Qualified
- RoHS Compliant

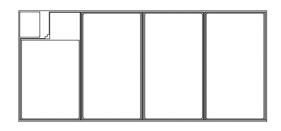
## DIMENSION (µm)

Die Size	4953×2413
Die Size (Sawn)	$4933 \pm 15 \times 2393 \pm 15$
Source Attach Area	1114.8 × 1648.9, (1114.8 × 2205.8) × 3
Gate Attach Area	385 × 535
Die Thickness	101.6 ±19.1

Gate and Source: AlSiCu Drain: Ti-NiV-Ag (back side of die)

Passivation: Polyimide Wafer Diameter: 8 inch Wafer Sawn on UV Tape Bad Dice Identified in Inking Gross Die Counts: 2113

The Chip is 100% Probed to Meet the Conditions and Limits Specified at  $T_J$  = 25°C.



## **ORDERING INFORMATION**

Device	Package		
NVCR4LS004N10MCA	Wafer		
	Sawn on Foil		

## RECOMMENDED STORAGE CONDITIONS

Temperature	22 to 28°C		
RH	40 to 66%		

Symbol	Parameter	Condition	Min	Тур	Max	Unit
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_D = 250 \ \mu A, \ V_{GS} = 0 \ V$	100	-	-	V
I <sub>DSS</sub>	Drain to Source Leakage Current	V <sub>DS</sub> = 100 V, V <sub>GS</sub> = 0 V	-	-	1	μΑ
I <sub>GSS</sub>	Gate to Source Leakage Current	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$	-	-	±100	nA
V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	2.0	-	4.0	V
*R <sub>DS(on)</sub>	Bare Die Drain to Source On Resistance	I <sub>D</sub> = 5 A, V <sub>GS</sub> = 10 V	-	3.2	4.0	mΩ
V <sub>SD</sub>	Source to Drain Diode Voltage	I <sub>SD</sub> = 5 A, V <sub>GS</sub> = 0 V	_	-	1.2	V
E <sub>AS</sub>	Single Pulse Drain-to-Source Avalanche Energy	L = 30 μH, I <sub>AS</sub> = 79 A	93.6	ı	-	mJ

<sup>\*</sup>Accurate R<sub>DS(on)</sub> test at die level is not feasible for this thin die as limited by the test contact precision attainable in a die form. The max R<sub>DS(on)</sub> specification is defined from the historical performance of the die in package but is not guaranteed by test in production. The die R<sub>DS(on)</sub> performance depends on the Source wire/ribbon bonding layout.

#### MOSFET MAXIMUM RATINGS in Reference to the FDBL86066-F085 electrical data in TOLL

(T<sub>J</sub> = 25°C unless otherwise noted)

Symbol	Parameter	Ratings	Unit
V <sub>DSS</sub>	Drain to Source Voltage	100	V
$V_{GS}$	Gate to Source Voltage ±20		V
I <sub>D</sub>	Continuous Drain Current $R_{\theta JC}$ ( $V_{GS}$ = 10) (Note 1) $T_{C}$ = 25°C $T_{C}$ = 100°C	184 130	A
E <sub>AS</sub>	Single Pulse Avalanche Energy (Note 2)	93.6	mJ
P <sub>D</sub>	Power Dissipation R <sub>0JC</sub>	300	W
	Derate Above 25°C	2	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature	-55 to +175	°C
$R_{ heta JC}$	Thermal Resistance, Junction to Case	0.5	°C/W
$R_{ heta JA}$	Maximum Thermal Resistance, Junction to Ambient (Note 3)	43	°C/W

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

- 1. Current is limited by silicon.
- 2. Starting  $T_J = 25^{\circ}C$ ,  $L = 30 \,\mu\text{H}$ ,  $I_{AS} = 79 \,\text{A}$ ,  $V_{DD} = 100 \,\text{V}$  during inductor charging and  $V_{DD} = 0 \,\text{V}$  during time in avalanche. 3.  $R_{\theta JA}$  is the sum of the junction–to–case and case–to–ambient thermal resistance, where the case thermal reference is defined as the solder mounting surface of the drain pins.  $R_{\theta JC}$  is guaranteed by design, while  $R_{\theta JA}$  is determined by the board design. The maximum rating presented here is based on mounting on a 1 in<sup>2</sup> pad of 2oz copper.

## ELECTRICAL CHARACTERISTICS in Reference to the FDBL86066-F085 electrical data in TOLL

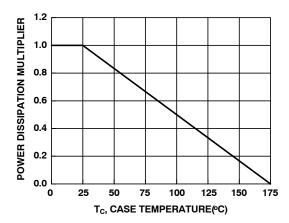
 $(T_J = 25^{\circ}C \text{ unless otherwise noted})$ 

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
OFF CHARAC	CTERISTICS		•			
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	I <sub>D</sub> = 250 μA, V <sub>GS</sub> = 0 V	100	_	-	V
I <sub>DSS</sub>	Drain to Source Leakage Current	V <sub>DS</sub> = 100 V, V <sub>GS</sub> = 0 V	-	-	1	μΑ
I <sub>GSS</sub>	Gate to Source Leakage Current	V <sub>GS</sub> = ±20 V	-	_	±100	nA
ON CHARACT	TERISTICS					
V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$	2.0	_	4.0	V
R <sub>DS(on)</sub>	Drain to Source on Resistance	$I_D = 80 \text{ A},   T_J = 25^{\circ}\text{C}$	-	3.3	4.1	mΩ
		$V_{GS} = 10 \text{ V}$ $T_{J} = 175^{\circ}\text{C (Note 4)}$	-	7.3	8.8	mΩ
DYNAMIC CH	ARACTERISTICS					
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> = 50 V, V <sub>GS</sub> = 0 V, f = 1 MHz	-	3240	_	pF
C <sub>oss</sub>	Output Capacitance		_	1950	-	pF
C <sub>rss</sub>	Reverse Transfer Capacitance		-	26	-	pF
$R_{g}$	Gate Resistance	f = 1 MHz	-	0.5	-	Ω
$Q_{g(ToT)}$	Total Gate Charge	$V_{GS} = 0$ to 10 V, $V_{DD} = 50$ V, $I_D = 80$ A	_	47	-	nC
$Q_{g(th)}$	Threshold Gate Charge	$V_{GS} = 0 \text{ to } 2 \text{ V}, V_{DD} = 50 \text{ V}, I_D = 80 \text{ A}$	-	6	-	nC
$Q_{gs}$	Gate to Source Gate Charge	V <sub>DD</sub> = 50 V, I <sub>D</sub> = 80 A	-	15	-	nC
$Q_qd$	Gate to Drain "Miller" Charge		-	10	-	nC
SWITCHING (	CHARACTERISTICS					
t <sub>d(on)</sub>	Turn-On Delay	V <sub>DD</sub> = 50 V, I <sub>D</sub> = 80 A,	-	18	-	ns
t <sub>r</sub>	Rise Time	$V_{GS}$ = 10 V, $R_{GEN}$ = 6 $\Omega$	_	9	-	ns
t <sub>d(off)</sub>	Turn-Off Delay	1	_	36	-	ns
t <sub>f</sub>	Fall Time	1	-	13	-	ns
DRAIN-SOUP	RCE DIODE CHARACTERISTIC	•	-		-	
V <sub>SD</sub>	Source to Drain Diode Voltage	I <sub>SD</sub> = 80 A, V <sub>GS</sub> = 0 V	_	-	1.25	V
		I <sub>SD</sub> = 40 A, V <sub>GS</sub> = 0 V	-	_	1.2	V
t <sub>rr</sub>	Reverse Recovery Time	I <sub>F</sub> = 80 A, dI <sub>SD</sub> /dt = 1000 A/μs	-	32	-	ns
Q <sub>rr</sub>	Reverse Recovery Charge	7	_	243	_	nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

<sup>4.</sup> The maximum value is specified by design at T<sub>J</sub> = 175°C. Product is not tested to this condition in production.

## **TYPICAL CHARACTERISTICS**



200 CURRENT LIMITED V<sub>GS</sub> = 10 V BY SILICON ID, DRAIN CURRENT (A) 160 120 80 40 0 25 50 75 100 125 150 175 T<sub>C</sub>, CASE TEMPERATURE(°C)

Figure 1. Normalized Power Dissipation vs. Case Temperature

Figure 2. Maximum Continuous Drain Current vs.

Case Temperature

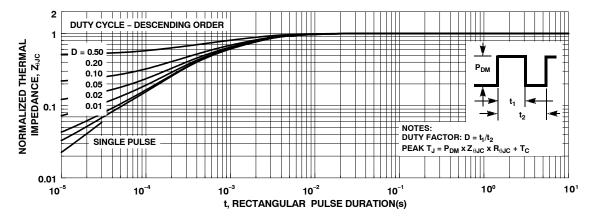


Figure 3. Normalized Maximum Transient Thermal Impedance

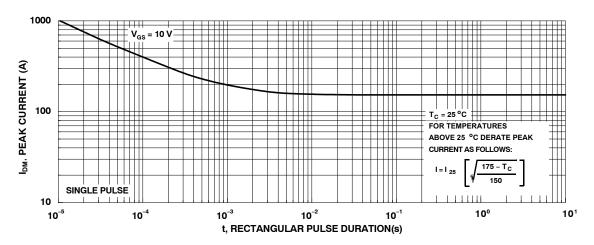


Figure 4. Peak Current Capability

## TYPICAL CHARACTERISTICS (continued)

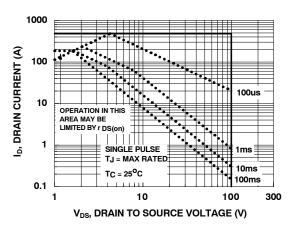


Figure 5. Forward Bias Safe Operating Area

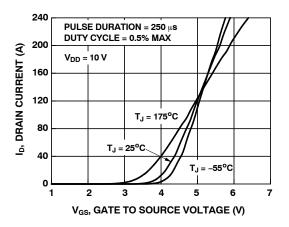


Figure 7. Transfer Characteristics

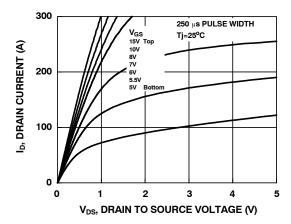


Figure 9. Saturation Characteristics

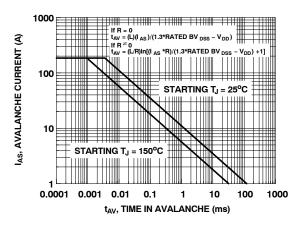


Figure 6. Unclamped Inductive Switching Capability

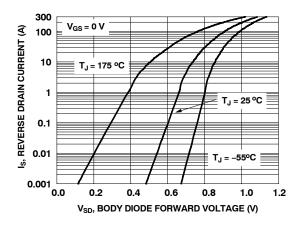


Figure 8. Forward Diode Characteristics

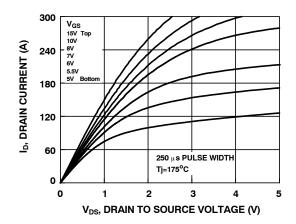


Figure 10. Saturation Characteristics

## TYPICAL CHARACTERISTICS (continued)

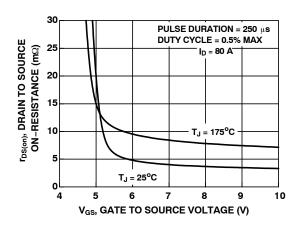


Figure 11. R<sub>DS(on)</sub> vs. Gate Voltage

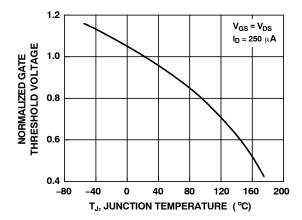


Figure 13. Normalized Gate Threshold Voltage vs. Temperature

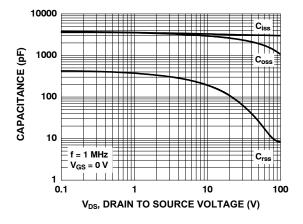


Figure 15. Capacitance vs. Drain to Source Voltage

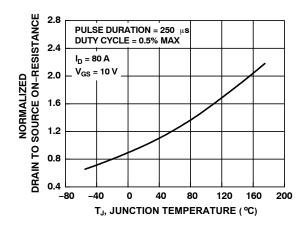


Figure 12. Normalized R<sub>DS(on)</sub> vs. Junction Temperature

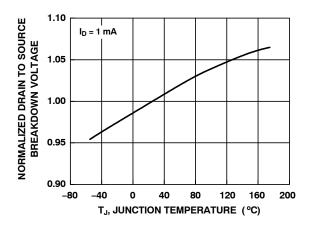


Figure 14. Normalized Drain to Source Breakdown Voltage vs. Junction Temperature

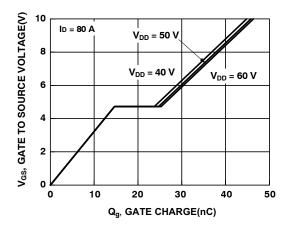


Figure 16. Gate Charge vs. Gate to Source Voltage

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